

– Microbunching at FLASH – Measurement of Coherent Radiation from 350 nm to 23 μm .

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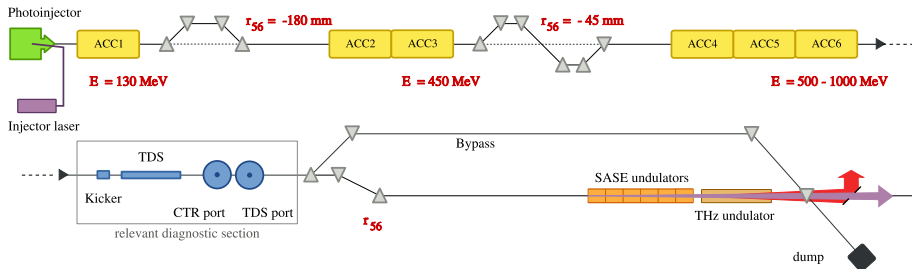
Deutsches Elektronen-Synchrotron, Hamburg

Workshop on the Microbunching Instability III – Frascati



FLASH - Overview

Status 2009 - before shutdown

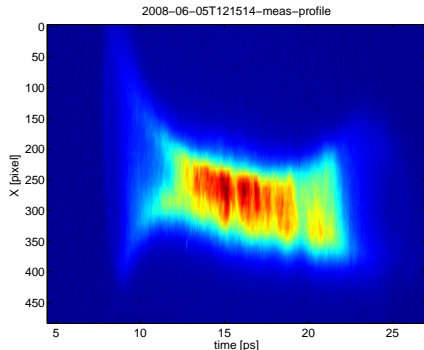


Inspection of incoherent and coherent transition radiation:

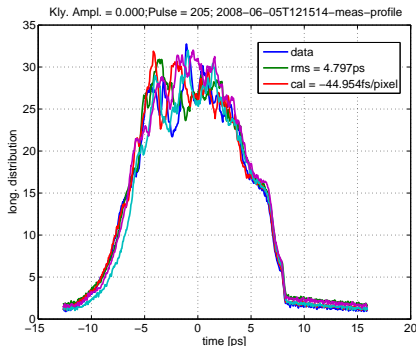
- deflection of single bunch onto off-axis screens (distance CTR-TDS port: $\sim 2 \text{ m}$)
- CTR port leads to external lab via evacuated beamline ($\sim 20 \text{ m}$)
- TDS port leads to optical table inside tunnel ($\sim 1 \text{ m}$)
- position in front of dogleg (\rightarrow not entirely compressed bunch)

First Microbunching observations

Transverse deflecting device



screen image of streaked electron bunch



longitudinal projection

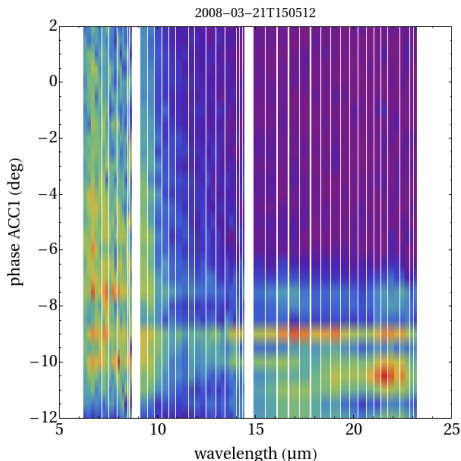
Uncompressed bunch: (nearly oncrest phases)

- ripples on longitudinal charge image
- strong fluctuation from shot to shot

courtesy Holger Schlarb

First Microbunching observations II

2 stage single shot spectrometer



Phasescan of ACC1:

- leading spike generates coherent signal over full wavelength range for $\varphi_{\text{ACC1}} < -7^\circ$
- CTR intensity below $\lambda \leq 13 \mu\text{m}$ is nearly independent of phase changes
- indication of microstructures inside electron bunch
- triggered intensive studies at smaller wavelengths

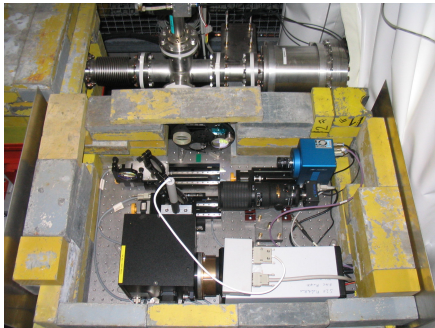
Experimental Equipment

Used spectrometers

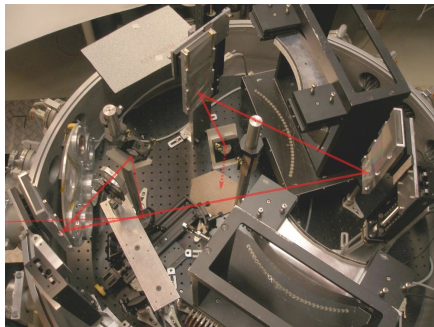
regime	spectrometer	detector	range	location	sensitive to incoh. level
VIS	commercial SP2150 $g = 1200 \text{ l} \cdot \text{mm}^{-1}$	ICCD (<i>S20</i>)	$0.3 - 0.85 \text{ } \mu\text{m}$	tunnel	YES
NIR	commercial SP2150 $g = 300 \text{ l} \cdot \text{mm}^{-1}$	CCD (<i>InGaAs</i>)	$0.8 - 1.6 \text{ } \mu\text{m}$	lab	NO
FIR	2 stage single shot $g = \{240, 150\} \text{ l} \cdot \text{mm}^{-1}$ $g = \{90, 54\} \text{ l} \cdot \text{mm}^{-1}$	pyro (<i>LiTaO₃</i>)	$3.4 - 23 \text{ } \mu\text{m}$	lab	NO

Experimental Equipment II

Installations



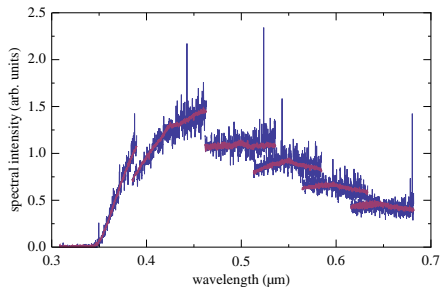
setup of optical table near TDS viewport



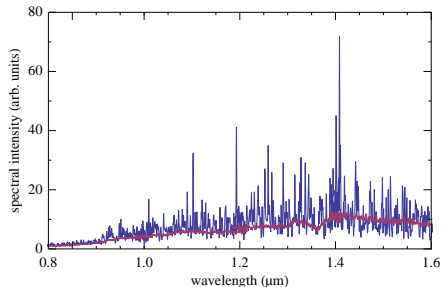
2 stage spectrometer in external laboratory

Measurement

Raw data examples



VIS spectra at $\lambda_c \in \{350, 425, 500, 550, 600, 650\}$ nm



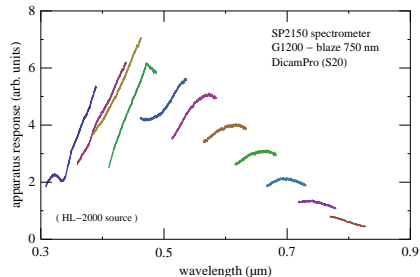
NIR spectra at $\lambda_c \in \{0.9, 1.1, 1.3, 1.5\}$ μm

Analysis procedure

VIS + NIR regime

Relative adjustment in VIS:

- camera QE(λ)
 - camera QE(x, y)
 - grating efficiency
(simulation with *PCGrate6.1* failed)
- response function of the whole system measured with calib. source!



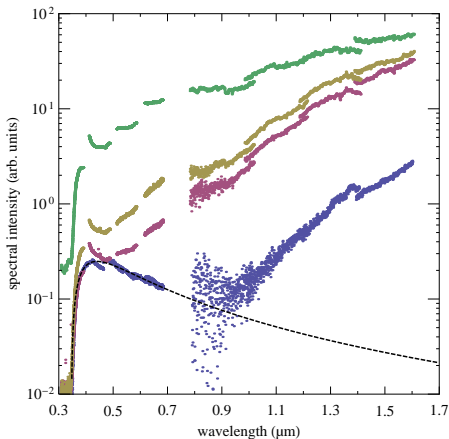
response of grating and camera in VIS regime

Relative adjustment in NIR:

- line array QE(λ)
- grating efficiency
(simulation delivers plausible results)

Data analysis

VIS + NIR spectra

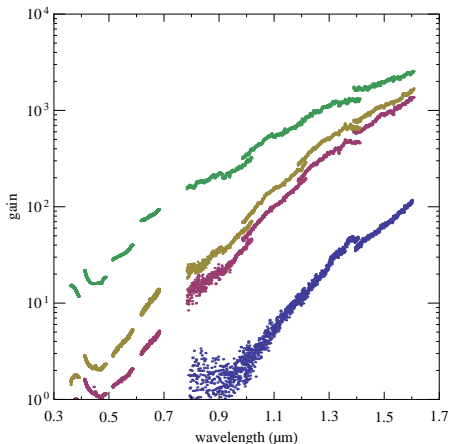


- FEL mode
 $r_{56,BC2} = -185 \text{ mm} / r_{56,BC3} = -55 \text{ mm}$
- oncrest phases
 $r_{56,BC2} = -185 \text{ mm} / r_{56,BC3} = -55 \text{ mm}$
- oncrest phases
 $r_{56,BC2} = -130 \text{ mm} / r_{56,BC3} = -55 \text{ mm}$
- oncrest phases
 $r_{56,BC2} = -130 \text{ mm} / r_{56,BC3} = -20 \text{ mm}$
- FEL mode fit

- FEL mode in VIS regime follows λ^{-2} + cut-off (optics)
- extension to longer wavelength defines incoherent level in NIR regime
- NIR spectra adjusted by ONE factor to VIS spectra

Data analysis II

VIS + NIR gain



- FEL mode
 $r_{56,BC2} = -185 \text{ mm} / r_{56,BC3} = -55 \text{ mm}$
- oncrest phases
 $r_{56,BC2} = -185 \text{ mm} / r_{56,BC3} = -55 \text{ mm}$
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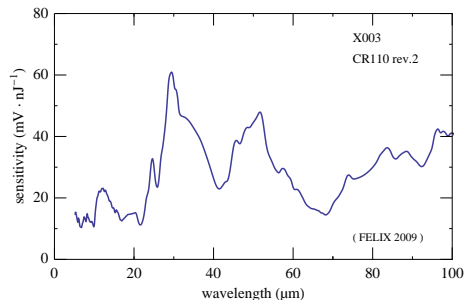
- $\text{gain}(\lambda) \equiv I_{\text{total}}(\lambda) / I_{\text{incoh.}}(\lambda)$
- exponential grow of gain (over 3 orders of magnitude)!
- different influence of BC2 and BC3 on intensity
- for smallest r_{56} 's COTR exceeds into the ultraviolet

Analysis procedure II

FIR regime

Absolute adjustment:

- polarizer efficiency
- grating efficiency
(simulations with *PCGrate6.1* and *GSolver4.2* agree)
- response of pyroelectric elements
(calibration at FELIX)



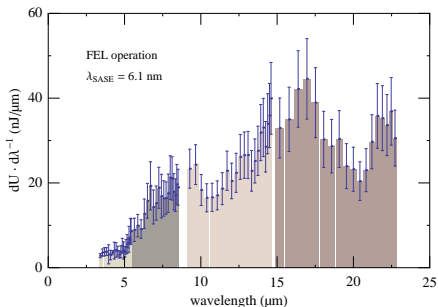
response of detector + electronics

Gain calculation:

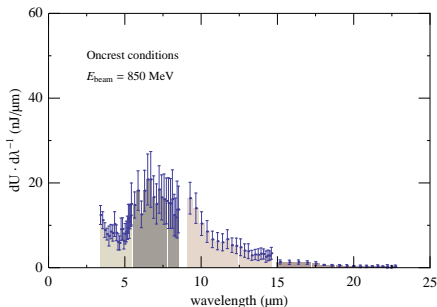
- Calculation of emitted TR through beamline to the external lab
(*THzTransport*: flattop bunch, diamond window, finite mirror size, gold coating of mirrors)
- measured spectra normalized to simulated spectra for incoherent emission

Data analysis III

FIR spectra



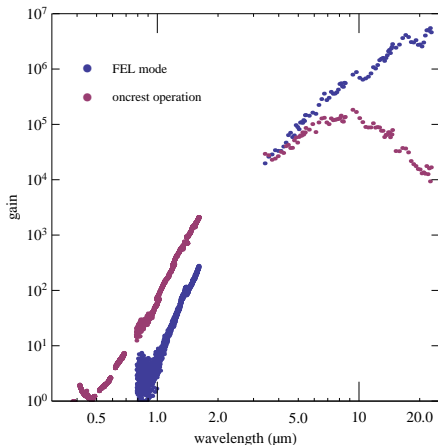
FEL mode CTR spectrum



oncrest CTR spectrum

Data analysis IV

Gain level



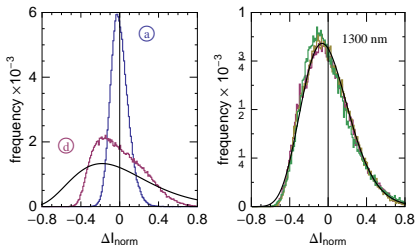
combination of data sets:

- same compressor settings
- mixing of microbunching signal and gain signature of compressed bunch (no separation)
- pure microbunching signal due to few ps long uncompressed bunch
- maximum gain of ~ 100.000
- $\lambda_{opt} \sim 9 \mu\text{m}$
- good agreement between different analysis procedures

Fluctuations

- fluctuation strength δ is given by number of modes m : $\delta^2 = 1/m$ ($m \gg 1$)
- fluctuation is described by Γ distribution with m modes

$$m = \sqrt{1 + 4\sigma_\omega^2 \sigma_t^2} \cdot \left(1 + 4k^2 \sigma_\theta^2 \sigma_\perp^2\right) \quad \text{Sannibale et al., PRST032801(2009)}$$



FEL mode (550 nm):

- fluctuation described by Γ dist. with $m \sim 80$
 - rough estimation: $\sigma_\omega = \text{spec.res.}$, $\sigma_t = 4 \text{ ps}$, $\sigma_\theta = 1/\gamma$, $\sigma_\perp = 150 \mu\text{m}$
- $m = 70$

Oncrest mode (1300 nm):

- fluctuation described by Γ dist. with $m = 15$
 - number is only given by longitudinal term, transverse mode has to be 1
- bunch seems to be fully coherent in transverse plane!

Results

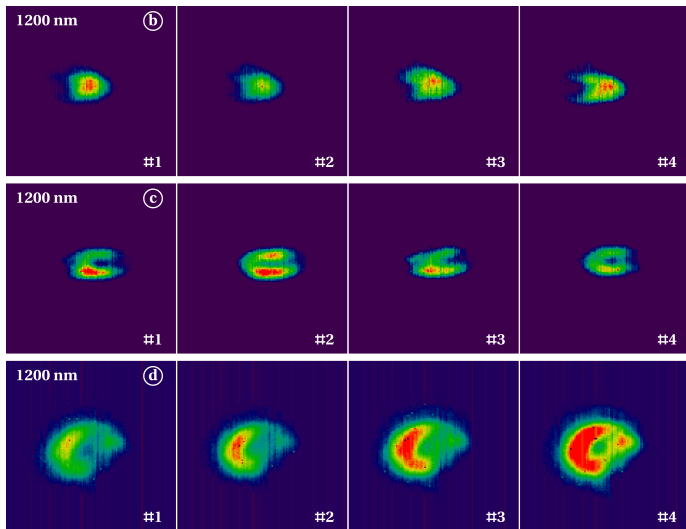
- transition radiation spectra from 350 nm to 23 μm for different machine settings were measured
- good understanding of used devices enables reasonable connection of gain spectra
- fluctuation analysis show fully transverse coherence
- data can be used to test analytical and numerical microbunching models

Outlook

Questions:

- Is the linearization of longitudinal phase space a problem for FLASH?
- Is it possible to model the instability quantitatively?
- What are the critical machine parameters to distinguish between models?

Closing



OTR screen images with InGaAs camera and 1200 nm bandpass filter ($\sigma = 10$ nm)